Application/Control No. Applicant(s)/Patent Under Reexamination 09/899,189 SEIDL ET AL. Notice of References Cited Art Unit Examiner Page 1 of 1 Hoai V Pham 2814 **U.S. PATENT DOCUMENTS** Document Number Date Name Classification Country Code-Number-Kind Code MM-YYYY Wei et al. US-6,251,722 06-2001 438/243 Α US-В US-С US-D US-Ε F US-US-G US-Н US-US-J US-Κ US-L US-М **FOREIGN PATENT DOCUMENTS** Document Number Date Country Name Classification Country Code-Number-Kind Code MM-YYYY Ν 0 Р Q R s Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U ٧ W

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Х